Search Notes

Application/Control N	lo. Applicant(s)/Patent und Reexamination	ier
09/815,446	BODE ET AL.	
Examiner	Art Unit	
Dwin M. Craig	2123	

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SEARCH NOT (INCLUDING SEARCH		')
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EAST (US-PGPUB, USPAT, USOCR) Inventor Name Search	11/23/2005	Dre
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) see search notes for search terms	11/23/2005	Durc
PALM (Inventor Name Search)	11/23/2005	m
GOOGLE (wafer, field error, mean, metrology, residual)	11/25/2005	onl
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) (overlay with budget) and wafer and residual	11/25/2005	Dne